

FOR PRECISION ANALOG, SENSORS, AND POWER APPLICATIONS

# Your Solution for Automotive and Precision Applications

Looking for solutions in the highly-competitive automotive and commercial market? You can rely on Johnstech to provide a highperformance, quality solution. Johnstech has taken all the best features found throughout the Spring Probe world and combined them into our designs.

### • Suitable for BGA, QFN, Leaded, and WLCSP applications.

- o Blade BGA, QFN, WLCSP, and Leaded
- o Fine QFN

### o Knife-Edge - BGA, WLCSP, and Leaded

• The DAISHO is designed in a single-ended architecture to minimize Cres variability.

• Fully user serviceable contactor architecture – individually replaceable probes

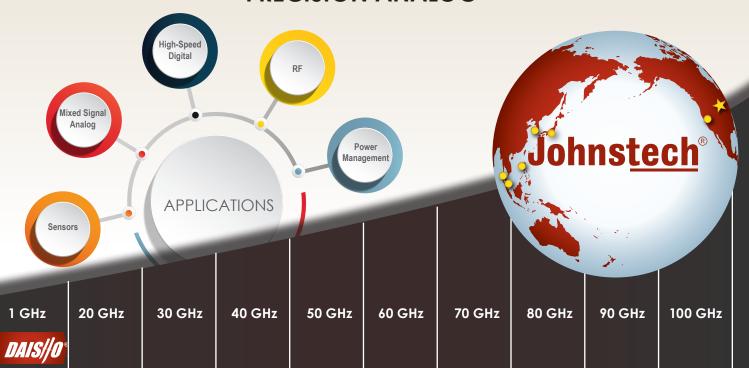
- · Pd alloy tips for easy cleaning
- · Compatible with a floating alignment plate for accuracy

A lot of experience and care went into the design of these probes to provide our customers with the best features. Johnstech studied several hundred BGA packages to understand ball diameters and heights that are most prevalent. We were able to optimize the tip geometry based on this exhaustive study of the market.

All Contactors will be available for Engineering test/characterization with a Manual Actuator and are ready for high-volume Automated Testing.

FEATURES & BENEFITS					
РІТСН	QFN ≥ 0.3mm; WLCSP and BGA ≥ 0.35mm; Leaded ≥ 0.4mm				
TEMPERATURE	-65°C to 175°C				
CURRENT CARRY CAPABILITY @1%; @100%	19.3A, 1.93A				
CONTACT RESISTANCE (mΩ)	40				
HIGH VOLTAGE CAPABLE (MATERIAL)	16.5kV @ 0.5mm 1.65 pA Leakage Current				





# **PRECISION ANALOG**



## **Electrical Specifications**

Probe Size/Pitch (mm)	Contact Resistance* (mΩ)	CCC 100% Duty Cycle (Amps)	CCC 1% DC RMS (Amps)	Loop Inductance (nH)
0.3 KNIFE	80	1.35	13.50	0.85
0.4 FINE	40	1.93	19.30	1.1
0.4 BLADE	40	1.93	19.30	1.1

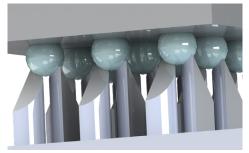
Results shown are typical for one size and configuration shown here. These charts are representative data. Please contact your Johnstech Sales Representative for additional specifications for specific test applications

\* Contact Resistance depends on maintenance, cleaning and device materials. The values shown are measured average based on a new probe.

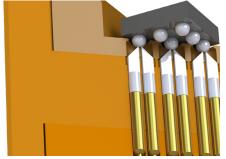
### **Mechanical Specifications**

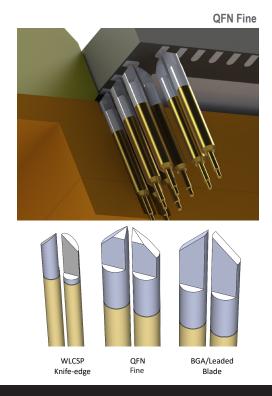
Probe Size/ Pitch (mm)	Minimum DUT Pitch (mm)	Test Height (mm)	Uncom- pressed Free Length FL (mm)	DUT Side Compliance (mm)	Total Stroke (mm)	Force at Test (g)	Minimum DUT Force-Sense Tip-Tip Spacing TT (mm)	Minimum PCB Force-Sense Pad Center Spacing P (mm)	Barrel Diameter B (mm)
0.3 KNIFE	0.30 QFN; 0.35 BGA	3.0	3.25	0.15	0.25	15	.070	0.28	0.21
0.4 FINE	0.40 QFN	3.22	3.62	0.30	0.40	20	0.70	0.40	0.33
0.4 BLADE	0.40 Leaded; 0.65 BGA	3.41	3.81	0.30	0.40	20	0.70	0.40	0.33

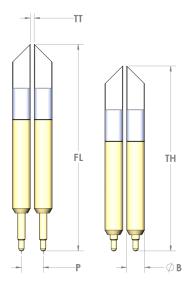
### WLCSP/BGA/Leaded Knife-Edge



WLCSP/ BGA/Leaded / QFN Blade









Johnstech International Corporation • 1210 New Brighton Boulevard • Minneapolis, MN 55413-1641 USA Tel 612.378.2020 • Fax 612.378.2030 • www.johnstech.com • E-mail info@johnstech.com

© Copyright 2021-22, Johnstech International Corporation. Specifications subject to change without notice. No part of this document may be reproduced in any form or by any means, electronic or mechanical, including photocopying, recording or by any information storage or retrieval system, without expressed written permission from Johnstech. Johnstech and Johnstech logo are registered trademarks in the USA and other countries. Johnstech products and components are covered by patents and copyrights in the USA and other countries. All other trademarks not owned by Johnstech, which appear within are the property of their respective owners. Please see, www. johnstech.com/IP for patent information.